

20 V, 3 A PNP low V_{CEsat} (BISS) transistor Rev. 02 — 15 January 2007

Product data sheet

Product profile

1.1 General description

PNP low V_{CEsat} Breakthrough In Small Signal (BISS) transistor in a medium power SOT89 (SC-62/TO-243) flat lead Surface-Mounted Device (SMD) plastic package.

NPN complement: 2PD2150.

1.2 Features

- Low collector-emitter saturation voltage V_{CEsat}
- High collector current capability I_C and I_{CM}
- High collector current gain (h_{FE}) at high I_C
- High efficiency due to less heat generation
- Smaller required Printed-Circuit Board (PCB) area than for conventional transistors

1.3 Applications

- DC-to-DC conversion
- MOSFET gate driving
- Motor control
- Charging circuits
- Power switches (e.g. motors, fans)
- Thin Film Transistor (TFT) backlight inverter

1.4 Quick reference data

Table 1. **Quick reference data**

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{CEO}	collector-emitter voltage	open base	-	-	-20	V
I_{C}	collector current		-	-	-3	Α
I _{CM}	peak collector current	single pulse; $t_p \le 1 \text{ ms}$	-	-	– 5	Α
V _{CEsat}	collector-emitter saturation voltage	$I_C = -2 A;$ $I_B = -0.1 A$	<u>[1]</u> -	-0.2	-0.5	V

[1] Pulse test: $t_p \le 300~\mu s;~\delta \le 0.02.$



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2. Pinning information

Table 2. Pinning

Table 2.	i iiiiiiig		
Pin	Description	Simplified outline	Symbol
1	emitter		
2	collector		2
3	base	3 2 1	3 —
			006aaa231

3. Ordering information

Table 3. Ordering information

Type number	Package					
	Name	Description	Version			
2PB1424	SC-62	plastic surface-mounted package; collector pad for good heat transfer; 3 leads	SOT89			

4. Marking

Table 4. Marking codes

Type number	Marking code
2PB1424	M1

5. Limiting values

Table 5. Limiting values

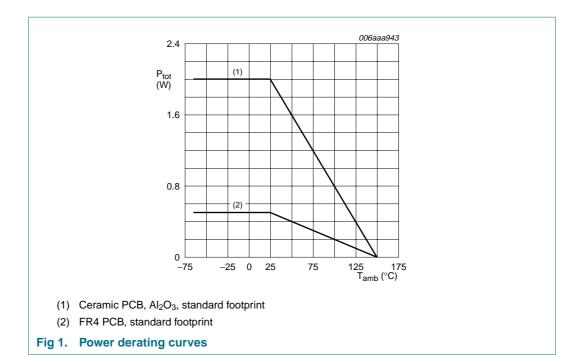
In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{CBO}	collector-base voltage	open emitter	-	-20	V
V_{CEO}	collector-emitter voltage	open base	-	-20	V
V_{EBO}	emitter-base voltage	open collector	-	-6	V
$I_{\mathbb{C}}$	collector current		-	-3	Α
I _{CM}	peak collector current	single pulse; $t_p \le 1 \text{ ms}$	-	-5	Α
P _{tot}	total power dissipation	$T_{amb} \le 25 ^{\circ}C$	<u>[1]</u> _	0.5	W
			[2] _	2	W
Tj	junction temperature		-	150	°C
T _{amb}	ambient temperature		-65	+150	°C
T_{stg}	storage temperature		-65	+150	°C

^[1] Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.

^[2] Device mounted on a ceramic PCB, Al₂O₃, standard footprint.

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6. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-a)}$	thermal resistance from	in free air	<u>[1]</u> -	-	250	K/W
junction to amb	junction to ambient		[2] _	-	62	K/W

^[1] Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.

^[2] Device mounted on a ceramic PCB, Al₂O₃, standard footprint.

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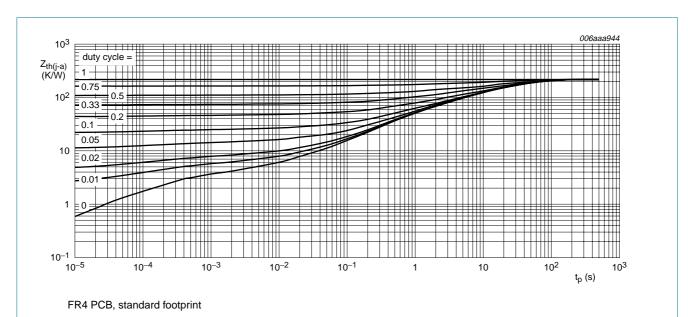


Fig 2. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

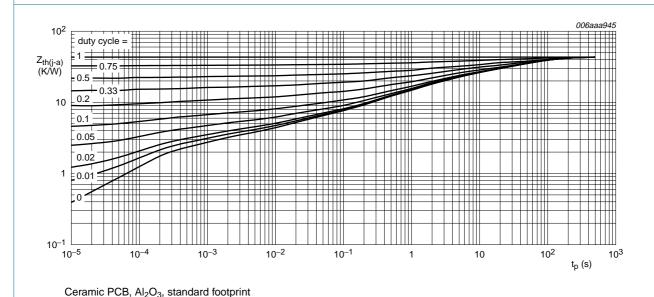


Fig 3. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

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7. Characteristics

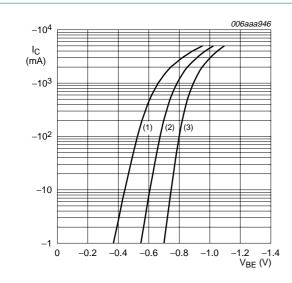
Table 7. Characteristics

 $T_{amb} = 25 \,^{\circ}C$ unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
I_{CBO}	collector-base cut-off current	$V_{CB} = -20 \text{ V}; I_E = 0 \text{ A}$	-	-	-0.1	μΑ
I _{EBO}	emitter-base cut-off current	$V_{EB} = -5 \text{ V}; I_C = 0 \text{ A}$	-	-	-0.1	μΑ
h _{FE}	DC current gain	$V_{CE} = -2 \text{ V}; I_{C} = -0.1 \text{ A}$	180	-	390	
V_{CEsat}	collector-emitter saturation voltage	$I_C = -2 A$; $I_B = -0.1 A$	<u>[1]</u> _	-0.2	-0.5	V
f _T	transition frequency	$V_{CE} = -2 \text{ V}; I_E = 0.5 \text{ A};$ f = 100 MHz	-	125	-	MHz
C_{ib}	common-base input capacitance	$V_{EB} = -5 \text{ V}; I_E = i_e = 0 \text{ A};$ f = 1 MHz	-	130	-	pF
C_ob	common-base output capacitance	$V_{CB} = -10 \text{ V}; I_E = i_e = 0 \text{ A};$ f = 1 MHz	-	37	-	pF

^[1] Pulse test: $t_p \le 300 \ \mu s; \ \delta \le 0.02.$

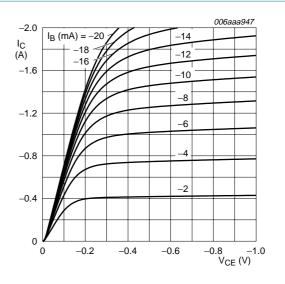
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 $V_{CE} = -2 V$

- (1) $T_{amb} = 100 \, ^{\circ}C$
- (2) $T_{amb} = 25 \,^{\circ}C$
- (3) $T_{amb} = -40 \, ^{\circ}C$

Fig 4. Collector current as a function of base-emitter voltage; typical values



T_{amb} = 25 °C

Fig 5. Collector current as a function of collector-emitter voltage; typical values

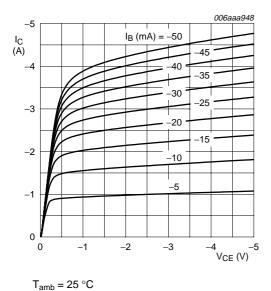
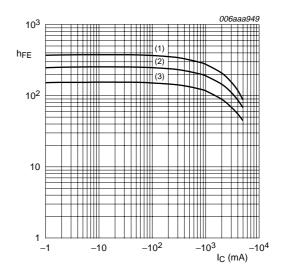


Fig 6. Collector current as a function of collector-emitter voltage; typical values

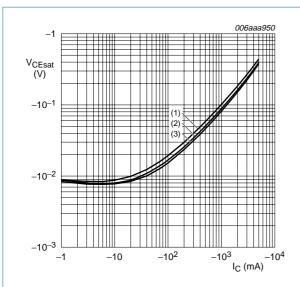


 $V_{CE} = -2 V$

- (1) $T_{amb} = 100 \, ^{\circ}C$
- (2) T_{amb} = 25 °C
- (3) $T_{amb} = -40 \, ^{\circ}C$

Fig 7. DC current gain as a function of collector current; typical values

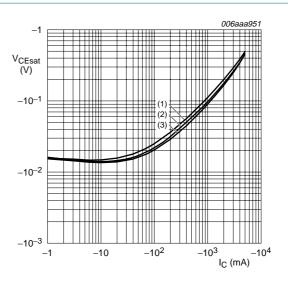
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$$I_{\rm C}/I_{\rm B} = 10$$

- (1) $T_{amb} = 100 \, ^{\circ}C$
- (2) $T_{amb} = 25 \, ^{\circ}C$
- (3) $T_{amb} = -40 \, ^{\circ}C$

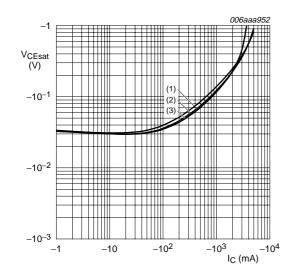
Fig 8. Collector-emitter saturation voltage as a function of collector current; typical values



$$I_{\rm C}/I_{\rm B} = 20$$

- (1) $T_{amb} = 100 \, ^{\circ}C$
- (2) $T_{amb} = 25 \, ^{\circ}C$
- (3) $T_{amb} = -40 \, ^{\circ}C$

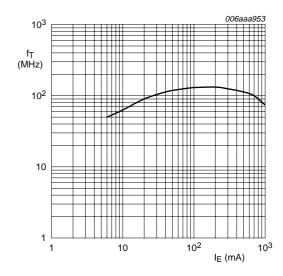
Fig 9. Collector-emitter saturation voltage as a function of collector current; typical values



 $I_{\rm C}/I_{\rm B}=50$

- (1) $T_{amb} = 100 \, ^{\circ}C$
- (2) $T_{amb} = 25 \, ^{\circ}C$
- (3) $T_{amb} = -40 \, ^{\circ}C$

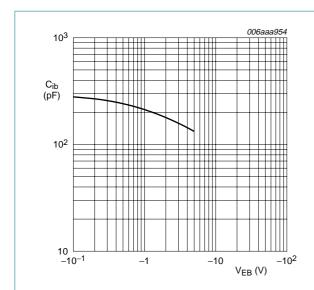
Fig 10. Collector-emitter saturation voltage as a function of collector current; typical values



 $T_{amb} = 25 \, ^{\circ}C; \, V_{CE} = -2 \, V$

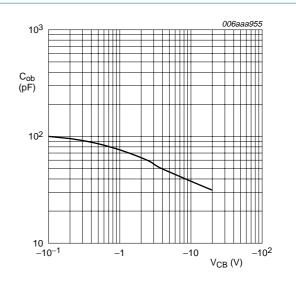
Fig 11. Transition frequency as a function of emitter current; typical values

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 T_{amb} = 25 °C; f = 1 MHz; I_E = i_e = 0 A

Fig 12. Common-base input capacitance as a function of emitter-base voltage; typical values



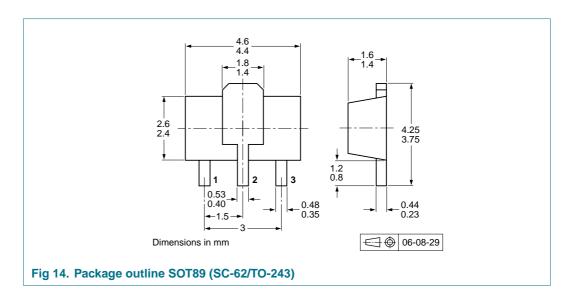
 T_{amb} = 25 °C; f = 1 MHz; I_E = i_e = 0 A

Fig 13. Common-base output capacitance as a function of collector-base voltage; typical values

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8. Package outline



9. Packing information

Table 8. Packing methods

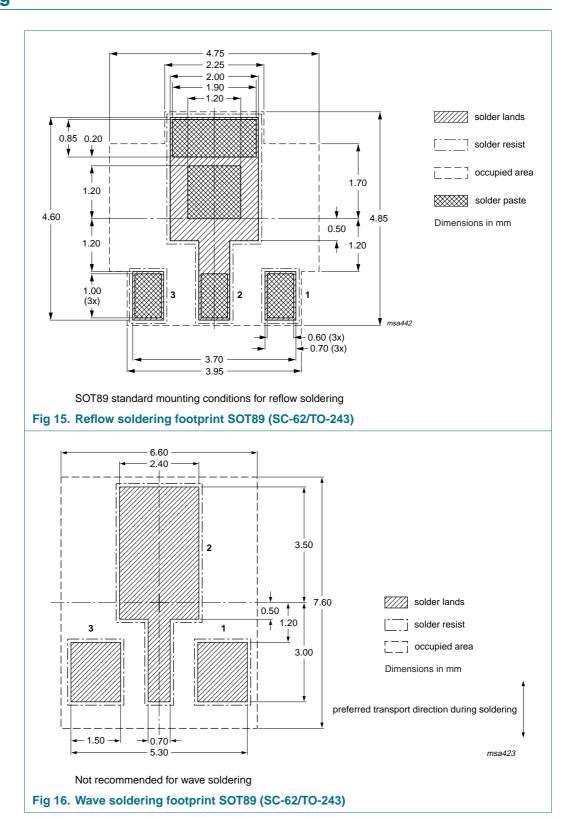
The indicated -xxx are the last three digits of the 12NC ordering code.[1]

Type number	Package	Description	Packing quantity	
			1000	4000
2PB1424	SOT89	8 mm pitch, 12 mm tape and reel	-115	-135

^[1] For further information and the availability of packing methods, see Section 13.

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10. Soldering



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11. Revision history

Table 9. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes		
2PB1424_2	20070115	Product data sheet	-	2PB1424_1		
Modifications:	 The format of t Semiconductor 	his data sheet has been redesiç rs.	gned to comply with the nev	v identity guidelines of NXP		
	 Legal texts have 	e been adapted to the new con	npany name where appropr	iate.		
	 Table 1 "Quick 	reference data": I _C collector cui	rent added			
	 Table 1 "Quick 	reference data": I _{CM} peak collection	ctor current maximum value	adapted		
	 Table 1 "Quick 	reference data": V _{CEsat} collecto	r-emitter saturation voltage	added		
	 Table 5 "Limitir 	ng values": V _{CBO} collector-base	voltage maximum value ad	apted		
	 <u>Table 5 "Limiting values"</u>: V_{EBO} emitter-base voltage maximum value adapted <u>Table 5 "Limiting values"</u>: I_C collector current maximum value adapted <u>Table 5 "Limiting values"</u>: I_{CM} peak collector current maximum value adapted 					
	 <u>Table 5 "Limiting values"</u>: P_{tot} total power dissipation for ceramic PCB condition added 					
	• Figure 1 "Power derating curves": adapted					
	Table 6 "Thermal characteristics": adapted					
	 <u>Table 6 "Thermal characteristics"</u>: R_{th(j-a)} thermal resistance from junction to ambient for ceramic PCB condition added 					
	 <u>Figure 2</u>: t_p pulse time redefined to pulse duration 					
	• Figure 3: added					
	 Table 7 "Chara 	cteristics": I _{CBO} collector-base of	cut-off current conditions ad	apted		
	 <u>Table 7 "Characteristics"</u>: V_{CEsat} collector-emitter saturation voltage typical value added 					
		cteristics": f _T transition frequence	•	lue adapted		
	 <u>Table 7 "Characteristics"</u>: C_{ib} common-base input capacitance added 					
	 <u>Table 7 "Characteristics"</u>: C_{ob} common-base output capacitance added 					
	• <u>Figure 4, 6, 10, 11, 12, 13</u> and <u>16</u> : added					
	• <u>Figure 5</u> , <u>7</u> , <u>8</u> and <u>9</u> : adapted					
	Section 12 "Le	gal information": updated				
2PB1424_1	20050502	Product data sheet	-	-		

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12. Legal information

12.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

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Date of release: 15 January 2007 Document identifier: 2PB1424_2